

November 2013

FQPF22N30

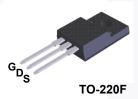
N-Channel QFET[®] MOSFET 300 V, 12 A, 160 m Ω

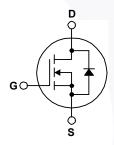
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- 12 A, 300 V, $R_{DS(on)}$ = 160 m Ω (Max.) @ V_{GS} = 10 V, I_D = 6 A
- Low Gate Charge (Typ. 47 nC)
- Low Crss (Typ. 40 pF)
- · 100% Avalanche Tested





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQPF22N30	Unit
V_{DSS}	Drain-Source Voltage		300	V
I _D	Drain Current - Continuous (T _C = 25°	C)	12	Α
	- Continuous (T _C = 100	°C)	7.6	A
I _{DM}	Drain Current - Pulsed	(Note 1)	48	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	1000	mJ
I _{AR}	Avalanche Current	(Note 1)	12	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.6	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		56	W
	- Derate above 25°C		0.45	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQPF22N30	Unit	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	2.23	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W	

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQPF22N30	FQPF22N30	TO-220F	Tube	N/A	N/A	50 units

Electrical Characteristics

T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Тур	Max	Uni
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	300			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°0	C	0.3		V/°C
Ince	Zero Gate Voltage Drain Current	V _{DS} = 300 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 240 V, T _C = 125°C			10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Cha	aracteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	3.0		5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 6 A		0.12	0.16	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 50 V, I _D = 6 A	\	12.5		S
C _{iss}	Input Capacitance Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		1700 350	2200 450	pF pF
	<u> </u>					•
C _{rss}	Reverse Transfer Capacitance	1.0 WH2		40	50	pF
	ing Characteristics			0.5	00	
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 150 \text{ V}, I_D = 22 \text{ A},$		35	80	ns
t _r	Turn-Off Delay Time	$R_G = 25 \Omega$		230 85	470 180	ns
t _{d(off)} t _f	Turn-Off Delay Time Turn-Off Fall Time	(Note	4)	100	210	ns
Կ Qg	Total Gate Charge	\ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \		47	60	ns nC
Q_{gs}	Gate-Source Charge	$V_{DS} = 240 \text{ V}, I_{D} = 22 \text{ A},$	/	12		nC
Q _{gd}	Gate-Drain Charge	V _{GS} = 10 V (Note 4)		24		nC
gu	Cate Brain Gharge		4)			
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				12	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				48	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 12 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 22 A,		215		ns
_						

Q_{rr}

Reverse Recovery Charge

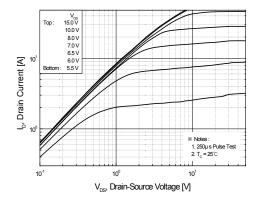
μС

1.6

 $dI_F / dt = 100 A/\mu s$

Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature. 2. L = 11.6 mH, I_{AS} = 12 A, V_{DD} = 50 V, R_{G} = 25 Ω , starting T_{J} = 25°C. 3. $I_{SD} \le 22$ A, di/dt ≤ 200 A/µs, $V_{DD} \le BV_{DSS}$, starting T_{J} = 25°C. 4. Essentially independent of operating temperature.

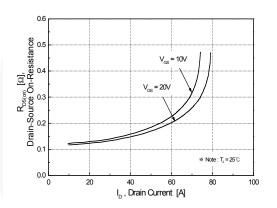
Typical Characteristics



| V_{SS} , Gatte-Source Voltage [V]

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



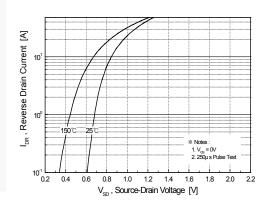
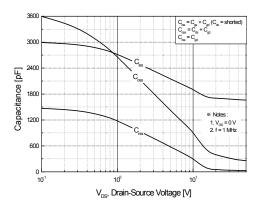


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature



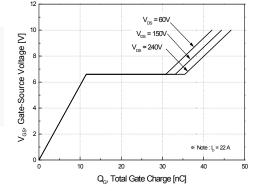


Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics

Typical Characteristics (continued)

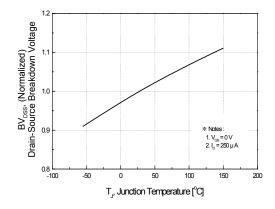
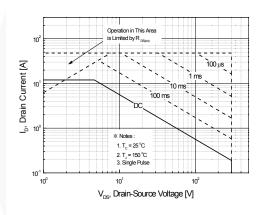


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



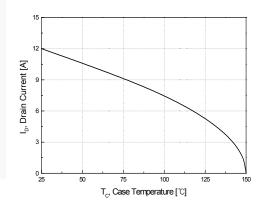


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

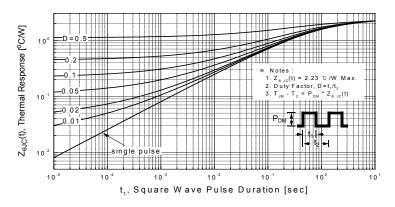


Figure 11. Transient Thermal Response Curve

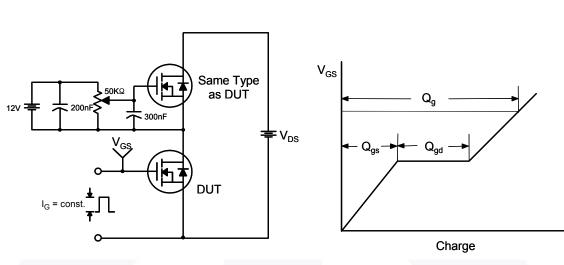


Figure 12. Gate Charge Test Circuit & Waveform

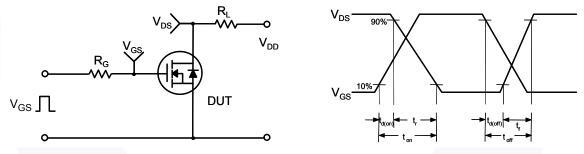


Figure 13. Resistive Switching Test Circuit & Waveforms

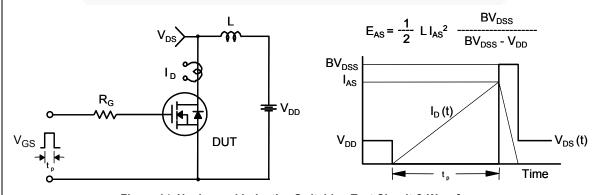
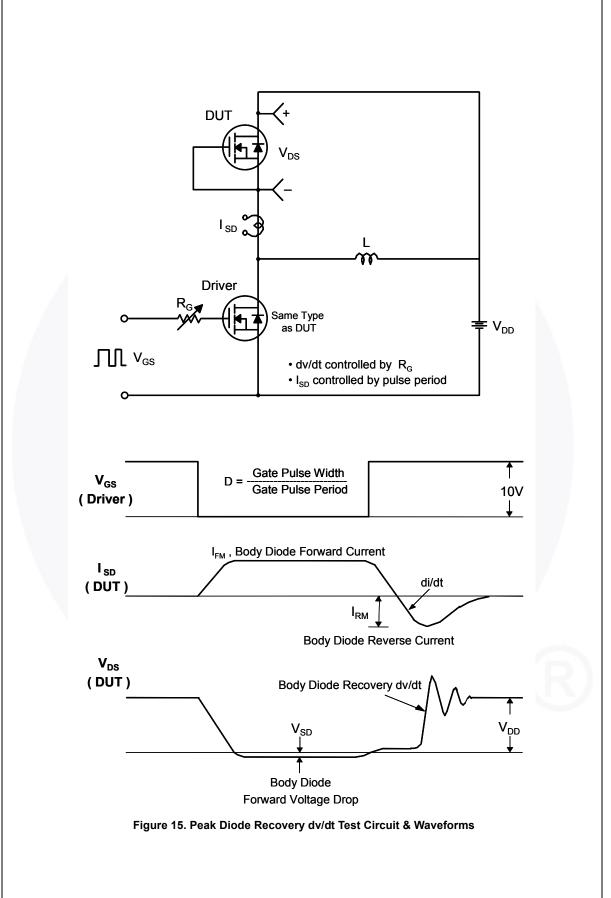


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



Mechanical Dimensions

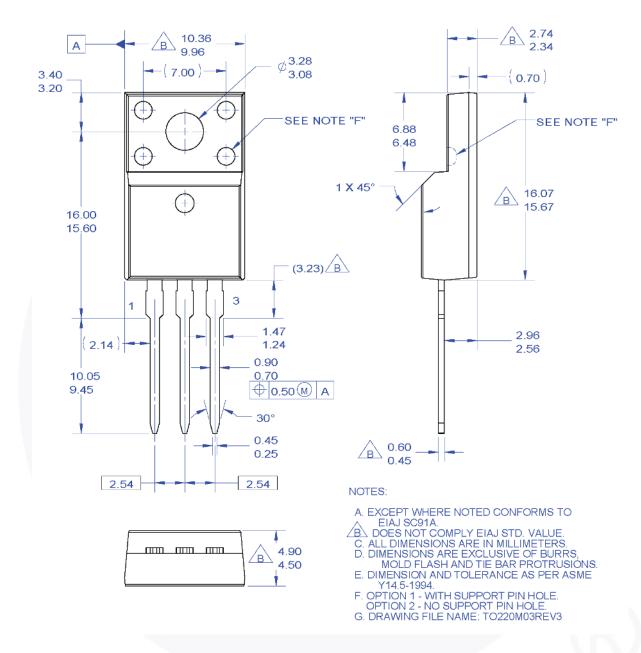


Figure 16. TO220, Molded, 3-Lead, Full Pack, EIAJ SC91, Straight Lead

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